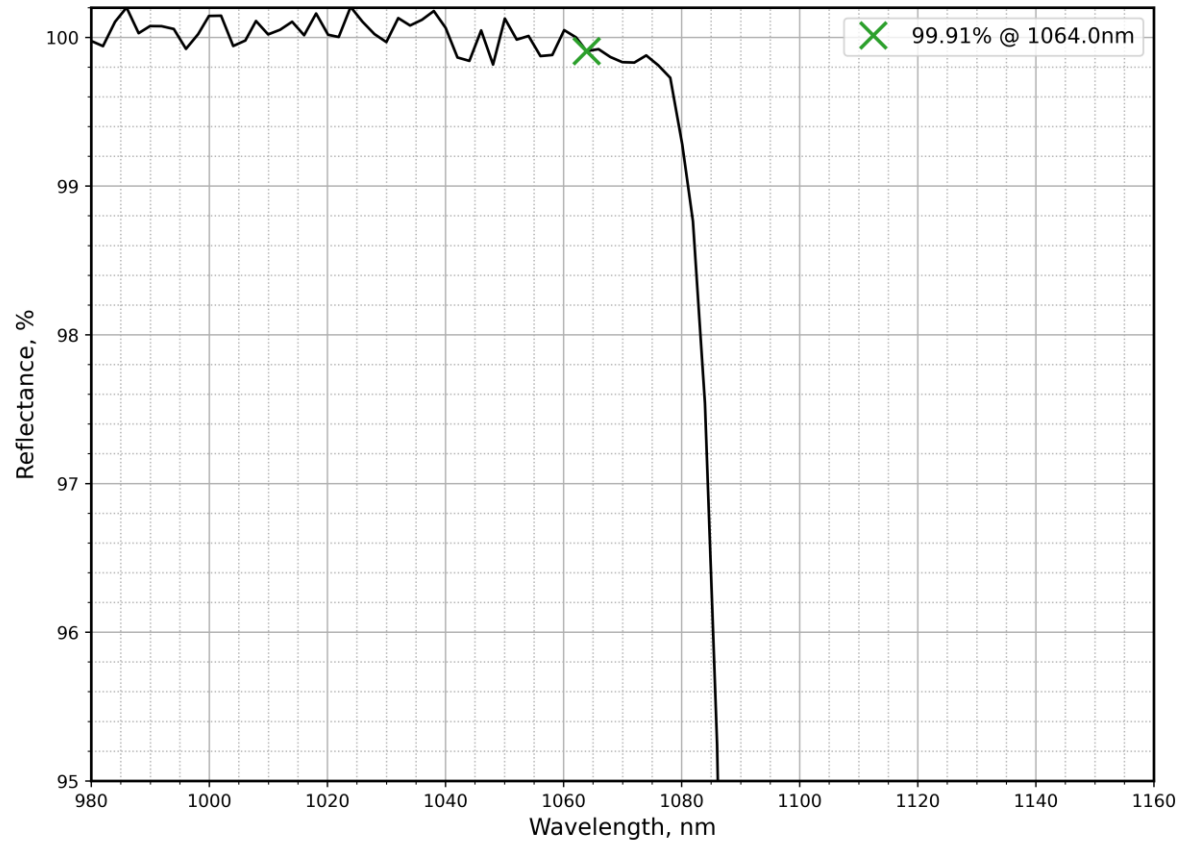


S1: (arrow marks)  $R_s > 99.9\% @ 1064 \text{ nm}$  +  $H T_p > 98\% @ 1064 \text{ nm}$  ( $T_p/T_s > 10001$ ),  $AOI = 45 \text{ deg} \pm 1 \text{ deg}$  (angle adjustment)  
S2:  $AR_p < 0.1\% @ 1064 \text{ nm}$ ,  $AOI = 45 \text{ deg}$



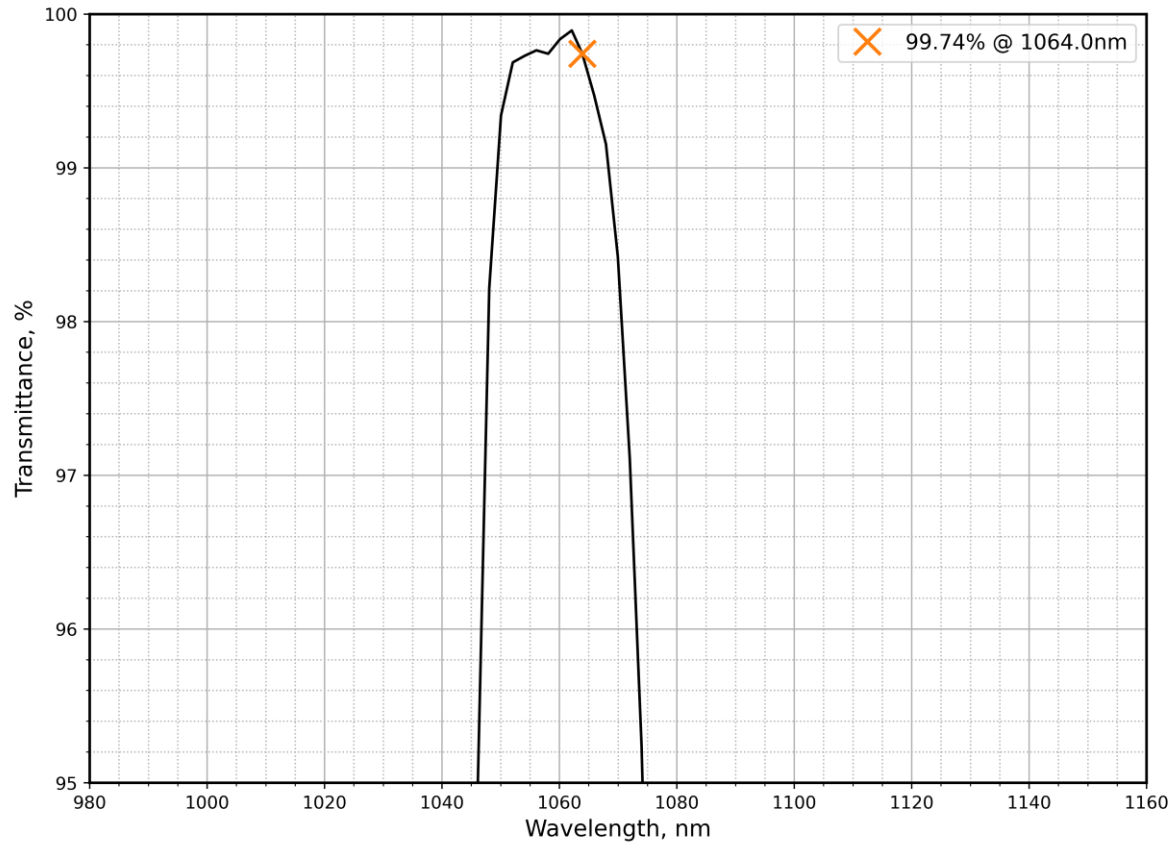
PO8464 Rs i45

Fig. 1.

SIDE MEASURED: S1+S2 (good component)

COMMENTS:

S1: (arrow marks)  $R_s > 99.9\%$  @ 1064 nm +  $H T_p > 98\%$  @ 1064 nm ( $T_p/T_s > 10001$ ), AOI=45 deg +/-1 deg (angle adjustment)  
 S2:  $A R_p < 0.1\%$  @ 1064 nm, AOI=45 deg



PO8464 Tp i45

Fig. 2.

SIDE MEASURED: S1+S2 (good component)

COMMENTS:

# LIDT TEST RESULTS

## LIDT VALUE

$10^3$ -on-1	$18.0^{+1.1}_{-1.2}$ J/cm <sup>2</sup>
$10^3$ -on-1 (scaled to 5.0 ns)	$12.8^{+0.8}_{-0.8}$ J/cm <sup>2</sup>

## CHARACTERISTIC DAMAGE CURVE

Table 1: Estimated LIDTs from fitting model for sample CAM117\_PAN7536.

Test mode	Pulse duration	Threshold (Offline detection - microscopy)	Threshold (Online detection - scattering)
1-on-1	9.8 ns	$19.6^{+0.3}_{-1.2}$ J/cm <sup>2</sup>	$23.5^{+0.4}_{-1.6}$ J/cm <sup>2</sup>
	scaled to 5.0 ns	$14.0^{+0.2}_{-0.9}$ J/cm <sup>2</sup>	$16.7^{+0.3}_{-1.1}$ J/cm <sup>2</sup>
10-on-1	9.8 ns	-	$18.0^{+1.3}_{-1.0}$ J/cm <sup>2</sup>
	scaled to 5.0 ns	-	$12.8^{+0.9}_{-0.7}$ J/cm <sup>2</sup>
$10^2$ -on-1	9.8 ns	-	$18.0^{+1.3}_{-1.0}$ J/cm <sup>2</sup>
	scaled to 5.0 ns	-	$12.8^{+0.9}_{-0.7}$ J/cm <sup>2</sup>
$10^3$ -on-1	9.8 ns	$18.0^{+1.1}_{-1.2}$ J/cm <sup>2</sup>	$18.0^{+1.3}_{-1.0}$ J/cm <sup>2</sup>
	scaled to 5.0 ns	$12.8^{+0.8}_{-0.8}$ J/cm <sup>2</sup>	$12.8^{+0.9}_{-0.7}$ J/cm <sup>2</sup>

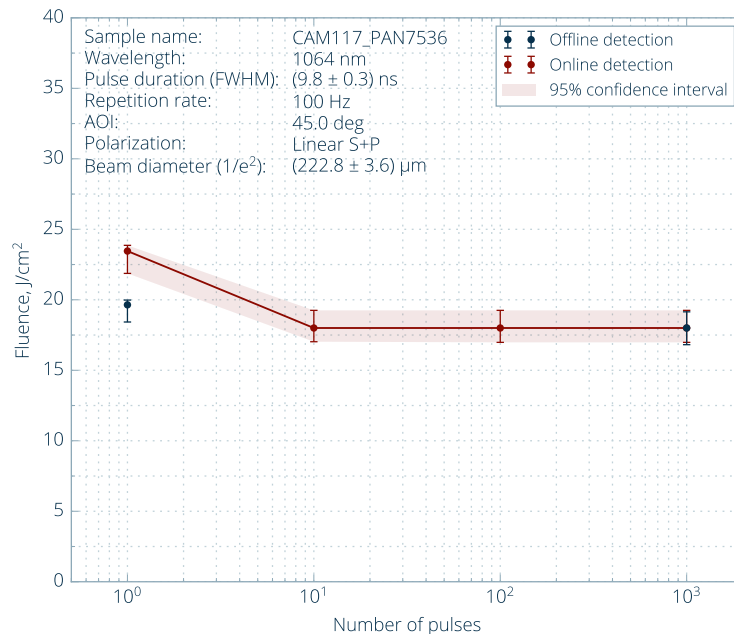


Figure 2. Characteristic damage curve.